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P/2699-26

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Toshikazu KITAJIMA et al. Date : February 1, 2005
Serial No. : 10/624,871 Group Art Unit : 2863
Filed : July 21, 2003 Examiner : Xiuquin Sun
Confirmation No. : 7650
For : FILM THICKNESS MEASURING METHOD, RELATIVE
DIELECTRIC CONSTANT MEASURING METHOD, FILM
THICKNESS MEASURING APPARATUS, AND RELATIVE
DIELECTRIC CONSTANT MEASURING APPARATUS

via FACSIMILE - (703) 872-9306

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT AFTER FINAL

Sir:

This is a response to the Office Action mailed November 3, 2004 in the above-identified application. Reconsideration of the application is respectfully requested.

FEE CALCULATION

Any additional fee required has been calculated as follows:

_____ If checked, "Small Entity" status is claimed.

NO. CLAIMS AFTER AMENDMENT		HIGHEST NO. PREVIOUSLY PAID FOR		EXTRA PRESENT		RATE	ADDIT. FEE
TOTAL	MINUS	TOTAL	MINUS	* =	** =		
11		20		-0-	X	(\$25 SE or \$50)	\$ -0-
INDEP. 3	MINUS	4		-0-	X	(\$100 SE or \$200)	\$ -0-
FIRST PRESENTATION OF MULTIPLE DEPENDENT CLAIM						X (\$180 SE or \$360)	\$ -0-
TOTAL \$							\$ -0-

* not less than 20

** not less than 3

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